

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10584971	SCHMIDT, EWALD
<b>Examiner</b>		<b>Art Unit</b>
DEAN O TAKAOKA		2817

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
333	109	2/2/09	DT
333	110	2/2/09	DT
333	111	2/2/09	DT
333	112	2/2/09	DT
333	113	2/2/09	DT
333	114	2/2/09	DT
333	115	2/2/09	DT
333	116	2/2/09	DT
333	238	2/4/09	DT

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
see attached	2/4/09	DT

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	all above	2/4/09	DT

	/D. O. T./ Primary Examiner.Alt Unit 2817
--	--